

## Freeform Search

---

<b>Database:</b>	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
<b>Term:</b>	(kaizen) and (dmaic)
<b>Display:</b>	<input type="text" value="50"/> Documents in <b>Display Format:</b> <input type="text" value="-"/> Starting with Number <input type="text" value="1"/>
<b>Generate:</b> <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

---

---

### Search History

---

**DATE:** Friday, May 06, 2005   
 [Printable Copy](#)   
 [Create Case](#)

<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
side by side			
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=NO; OP=OR</i>			
<u>L25</u>	(kaizen) and (dmaic)	2	<u>L25</u>
<u>L24</u>	(kaizen adj analysis) and (dmaic)	0	<u>L24</u>
<u>L23</u>	(integrat\$3 adj3 six adj sigma) and (dmaic)	3	<u>L23</u>
<u>L22</u>	(integrat\$3 adj3 six adj sigma) and (kaizen)	0	<u>L22</u>
<u>L21</u>	(six adj sigma) and (kaizen adj3 analyz\$5)	0	<u>L21</u>
<u>L20</u>	(six adj sigma) and kaizen	2	<u>L20</u>
<u>L19</u>	(kaizen adj analysis)	0	<u>L19</u>
<u>L18</u>	(six sigma kaizen schedule)	933703	<u>L18</u>
<u>L17</u>	(six sigma kaizen)	847773	<u>L17</u>
<u>L16</u>	(six adj sigma adj kaizen adj3 schedul\$3) and (kaizen)	0	<u>L16</u>
<u>L15</u>	(six adj sigma) and (kaizen adj analysis)	0	<u>L15</u>
<u>L14</u>	(six adj sigma) and (lean adj manufactur\$3) and (kaizen adj analysis)	0	<u>L14</u>
<u>L13</u>	(integrat\$4 adj3 six adj sigma) and (lean adj manufact\$3) and (kaizen adj analysis)	0	<u>L13</u>

<u>L12</u>	(level adj indicator) and (integrat\$4 adj3 six adj sigma) and (lean adj manufact\$3) and (kaizen adj analysis)	0	<u>L12</u>
<u>L11</u>	(integrat\$4 adj3 six adj sigma) and (lean adj manufactur\$3) and (kaizen adj analysis)	0	<u>L11</u>
<u>L10</u>	(integration adj3 six adj sigma) and (lean adj manufacturing) and (kaizen adj analysis)	0	<u>L10</u>
<u>L9</u>	(integration adj six adj sigma) and (lean adj manufacturing) and (kaizen adj analysis)	0	<u>L9</u>
<u>L8</u>	(analyz\$6 adj3 problem adj statement) and (level adj indicator) ann (integrat\$4 adj3 six adj sigma) and (lean adj manufact\$3) and (kaizen adj analysis)	138004	<u>L8</u>
<u>L7</u>	(analyz\$6 adj3 problem adj statement) and (level adj indicator) ann (integrat\$4 adj3 six adj sigma) and (lean adj manufact\$3) and (kaizen)	138004	<u>L7</u>
<u>L6</u>	schweizehorf.inv.	0	<u>L6</u>
<u>L5</u>	schweizehorf-e.inv.	0	<u>L5</u>
<u>L4</u>	mcrae.inv.	916	<u>L4</u>
<u>L3</u>	mcrae-k.inv.	0	<u>L3</u>
<u>L2</u>	mcrae-k.in.	0	<u>L2</u>
<u>L1</u>	mcrae-katherine.in.	0	<u>L1</u>

END OF SEARCH HISTORY

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

**Search Results**[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(kaizen&lt;and&gt;(integration six sigma&lt;in&gt;metadata))"

e-mail

Your search matched 0 of 105 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

[» View Session History](#)[» New Search](#)

Modify Search

[» Key](#)

IEEE JNL IEEE Journal or Magazine

☐ Check to search only within this results set

IEEE JNL IEE Journal or Magazine

Display Format: ☒ Citation ☐ Citation & Abstract

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEE Conference Proceeding

**No results were found.**

IEEE STD IEEE Standard

Please edit your search criteria and try again. Refer to the Help pages if you need assistance revisir

Indexed by  
[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE ...


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

Search Results

[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(kaizen&lt;and&gt;(six sigma&lt;in&gt;metadata))"

e-mail

Your search matched 4 of 105 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

[» View Session History](#)[» New Search](#)

Modify Search

» Key



IEEE JNL IEEE Journal or Magazine

☐ Check to search only within this results set

IEEE JNL IEE Journal or Magazine

Display Format: ☒ Citation ☐ Citation & Abstract

IEEE CNF IEEE Conference Proceeding

Select Article Information

IEEE CNF IEE Conference Proceeding

**1. Managing agility for profitability**

Hayman, A.N.;

Engineering Management Conference, 2004. Proceedings. 2004 IEEE International Volume 1, 18-21 Oct. 2004 Page(s):1 - 5 Vol.1

[AbstractPlus](#) | Full Text: [PDF\(626 KB\)](#) IEEE CNF**2. Inventory management Kaizen**

Palmer, V.S.;

Engineering Management for Applied Technology, 2001. EMAT 2001. Proceedings. 2nd Workshop on 16-17 Aug. 2001 Page(s):55 - 56

[AbstractPlus](#) | Full Text: [PDF\(274 KB\)](#) IEEE CNF**3. Lean Sigma [production and supply chain management]**

Antony, J.; Escamilla, J.L.; Caine, P.;

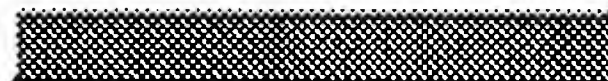
Manufacturing Engineer

Volume 82, Issue 2, April 2003 Page(s):40 - 42

[AbstractPlus](#) | Full Text: [PDF\(503 KB\)](#) IEEE JNL**4. Modelling of an integrated quality system using IDEF0**

Rowlands, H.; Richards, C.;

Industrial Electronics, 2002. ISIE 2002. Proceedings of the 2002 IEEE International Symposium on 8-11 July 2002 Page(s):1364 - 1369 vol.4

[AbstractPlus](#) | Full Text: [PDF\(618 KB\)](#) IEEE CNFindexed by  
 Inspec®[Help](#) [Contact Us](#) [Privacy & Policy](#)

© Copyright 2005 IEEE – All Rights Reserved

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

**Search Results**[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(kaizen&lt;and&gt;(dmaic schedule&lt;in&gt;metadata))"

☒ e-mail

Your search matched 0 of 105 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance** in **Descending** order.[» View Session History](#)[» New Search](#)

Modify Search

[» Key](#)IEEE JNL IEEE Journal or  
Magazine☐ Check to search only within this results setIEEE JNL IEE Journal or  
MagazineDisplay Format: ☒ Citation ☐ Citation & AbstractIEEE  
CNF IEEE Conference  
ProceedingIEEE CNF IEE Conference  
Proceeding**No results were found.**IEEE  
STD IEEE Standard

Please edit your search criteria and try again. Refer to the Help pages if you need assistance revisir

Indexed by  
 Inspec[Help](#) [Contact Us](#) [Privacy & ;](#)

© Copyright 2005 IEEE --



[Home](#) | [Login](#) | [Logout](#) | [Access information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

**Author Search**

**BROWSE**

**SEARCH**

**IEEE XPLORE GUIDE**



**OPTION 1**

**Quick Find an Author:**

Enter a name to locate articles written by that author.



Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.



**OPTION 2**

**Browse alphabetically**

Select a letter from the list.

**[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)**

Select a name to view articles written by that author

[Schweizer A.](#)

[Schweizer B.](#)

[Schweize](#)

[Schweizer G.](#)

[Schweizer H.](#)

[Schweize](#)

[Schweizer H. P.](#)

[Schweizer J.](#)

[Schweize](#)

[Schweizer M.](#)

[Schweizer M. A.](#)

[Schweize](#)

[Schweizer P.](#)

[Schweizer P. F.](#)

[Schweize](#)

[Schweizer R. C.](#)

[Schweizer S.](#)

[Schweize](#)

[Schweizer S. L.](#)

[Schweizer S. M.](#)

[Schweize](#)

[Schweizer T. C.](#)

[Schweizer Th.](#)

[Schweize](#)

Indexed by  
**Inspecc**

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE



[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

**Author Search**

**BROWSE**

**SEARCH**


**IEEE XPLORE GUIDE**



**OPTION 1**

**Quick Find an Author:**

Enter a name to locate articles written by that author.



Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.

Select a name to view articles written by that author

[McRae A.](#)

[McRae B.](#)

[McRae C.](#)

[McRae D. A.](#)

[McRae D. D.](#)

[McRae E.](#)

[McRae G. J.](#)

[McRae R.](#)

[McRae S.](#)



**OPTION 2**


**Browse alphabetically**

Select a letter from the list.

[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE

Indexed by  


[Home](#) | [Login](#) | [Logout](#) | [Access information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

[Author Search](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)**OPTION 1**

Quick Find an Author:

Enter a name to locate articles written by that author.



No Authors found beginning with letter: schweizerhof, evel

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.

**OPTION 2**

Browse alphabetically

Select a letter from the list.

[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

Indexed by

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE



[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

**Author Search**

**BROWSE**

**SEARCH**

**IEEE XPLORE GUIDE**



**OPTION 1**

**Quick Find an Author:**

Enter a name to locate articles written by that author.



**No Authors found beginning with letter: schweizerhof**

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.



**OPTION 2**

**Browse alphabetically**

Select a letter from the list.

**A B C D E F G H I J K L M N O P Q R S T U V W X Y Z**

Indexed by  
**Inspection**

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE